Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/790,777	TANAKA ET AL.	
Examiner	Art Unit	
Christopher RoDee	1756	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
1.00				

SEAR (INCLUDING S	CH NOTES EARCH STRAT	EGY)
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Search updated	6/19/2	006 CDR